

	Application No.	Applicant(s)	
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Notice of Allowability	10/618,446	MACGIBBON ET AL.	
Notice of Allowability	Examiner	Art Unit	
	Michael P. Stafira	2877	
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED i or other appropriate comm IGHTS. This application is	n this application. If not included unication will be mailed in due course. T	THIS nitiative
1. This communication is responsive to filing date 7/10/2003.			
2. The allowed claim(s) is/are <u>1-83</u> .			
 3. ☐ Acknowledgment is made of a claim for foreign priority unerstanding a) ☐ All b) ☐ Some* c) ☐ None of the: 1. ☐ Certified copies of the priority documents have 		or (f).	
Certified copies of the priority documents have		on No.	
Copies of the certified copies of the priority do			the
International Bureau (PCT Rule 17.2(a)).	cuments have been receive	a III and haddral dage application from	0
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		e a reply complying with the requirement	ts
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give	nitted. Note the attached EX es reason(s) why the oath o	AMINER'S AMENDMENT or NOTICE C r declaration is deficient.	F
5. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.		
(a) ☐ including changes required by the Notice of Draftspers	son's Patent Drawing Revie	w (PTO-948) attached	
1) hereto or 2) to Paper No./Mail Date			
(b) including changes required by the attached Examiner' Paper No./Mail Date	s Amendment / Comment o	r in the Office action of	
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t	i.84(c)) should be written on t the header according to 37 C	he drawings in the front (not the back) of FR 1.121(d).	
6. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT	osit of BIOLOGICAL MAT FOR THE DEPOSIT OF BI	ERIAL must be submitted. Note the OLOGICAL MATERIAL.	
• •			
Attachment(s) 1. ☑ Notice of References Cited (PTO-892)	5 \(\sqrt{\text{Notice of I}}	nformal Patent Application (PTO-152)	
 Notice of References Cited (FTO-092) Dotice of Draftperson's Patent Drawing Review (PTO-948) 		Summary (PTO-413),	
	Paper No	/Mail Date	
 Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 7/10/03 	08), 7. ☐ Examiner's	: Amendment/Comment	
4. Examiner's Comment Regarding Requirement for Deposit	8. 🛛 Examiner's	Statement of Reasons for Allowance	
of Biological Material	9. 🗌 Other		
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DETAILED ACTION

Allowable Subject Matter

- 1. Claims 1-83 are allowed over the prior art of record.
- 2. The following is an examiner's statement of reasons for allowance:

Regarding claim 1, the prior art fails to disclose or make obvious a method for locating/sizing contaminants on a bare, highly polished, and planar surface of a dielectric or semiconductor material having the steps of focusing a coherent beam of diffraction limited monochromatic P-polarized light from a solid-state light source and directed specifically at Brewster's angle to form a quasi-elliptical illuminated spot on the material surface which specularly reflects a circular minimal power beam from the surface of the material the cross-section of which has a dark central band and two outer low light lobes; causing a contaminant on the material surface to pass multiple times through the quasi-elliptical illuminated spot incident on the material surface so that the contaminant, on each pass through the illuminated spot, scatters the light in a quasi-hemispherical pattern, and in combination with the other recited limitations of claim 1. Claims 2-33 are allowed by the virtue of dependency on the allowed claim 1.

Regarding claim 34, the prior art fails to disclose or make obvious an apparatus for locating/sizing contaminants on a bare, highly polished, and planar surface of a dielectric or semiconductor material having a means for directing a focused coherent diffraction limited beam of monochromatic P-polarized light from a solid-state light source and specifically disposed at Brewster's angle to form a quasi-elliptical illuminated spot on the material surface that specularly

reflects a circular minimal power beam from the material surface the cross-section of which has a dark central band and two outer low light lobes; the center of said illuminated spot coincident with the focal point of the beam on the beam optical axis and on the material surface, and in combination with the other recited limitations of claim 34. Claims 35-83 are allowed by the virtue of dependency on the allowed claim 34.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Michael P. Stafira whose telephone number is 571-272-2430. The examiner can normally be reached on 4/10 Schedule Mon.-Thurs..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory Toatley can be reached on 571-272-2800 ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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Michael P. Stafira Primary Examiner Art Unit 2877

August 30, 2005